

INFORMATION DISCLOSURE CITATION

Atty. Docket No.	03180.0324	Serial No.	10/602,670
Applicants	Shunko MAGOSHI et al.		
Filing Date	June 25, 2003	Group:	



U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
<i>DE</i>	5,278,421	01/11/1994	Yoda et al.	250	492.22	
<i>KE</i>	6,243,487 B1	06/05/2001	Nakajima	382	144	

FOREIGN PATENT DOCUMENTS						
	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>ME</i>	Fumio MURAI et al., "Fast proximity effect correction method using a pattern area density map", J. Vac. Sci. Technol. B 10(6), Nov/Dec 1992, pp. 3072-3076

Examiner	<i>ZIA R. HASHI</i>	Date Considered	<i>4/7/04</i>
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			
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